

ELITE System (Enhanced lock-in thermal emission)



Defective or underperforming semiconductor devices often show an anomalous distribution of the local power dissipation, leading to local temperature increases.

Thermo Scientific™ ELITE system utilizes Lock-in IR Thermography (LIT), used in IC analysis to locate line shorts, ESD defects, oxide damage, defective transistors and diodes, and device latch-ups.

